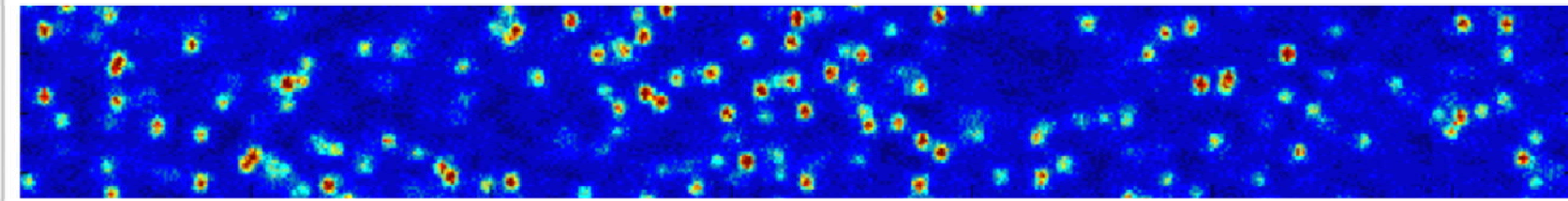


Nano-Particle Image Velocimetry (nPIV); Data Reduction Challenges

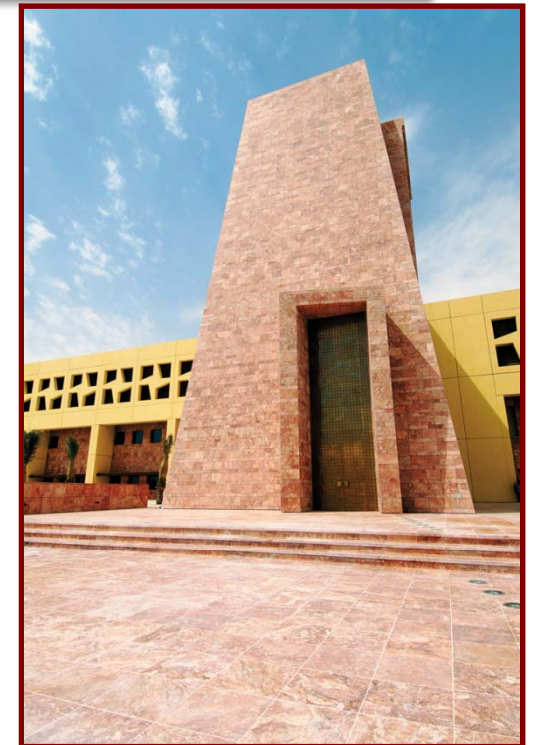


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OUTLINE

- Introduction
 - Nano Particle Image Velocimetry (nPIV)
 - Experimental set up
 - Numerical method
 - Theory & Simulation
- Results
 - Surface forces
 - Particle distribution near the wall
 - Effect of Brownian motion + non uniform illumination
 - Effect out of plane velocity gradient
- Experimental results
- Conclusions

nPIV

- New diagnostic technique to study near-wall flows at the sub-micron (“nano”) scale
- Measure two components of nearly instantaneous velocity parallel to wall

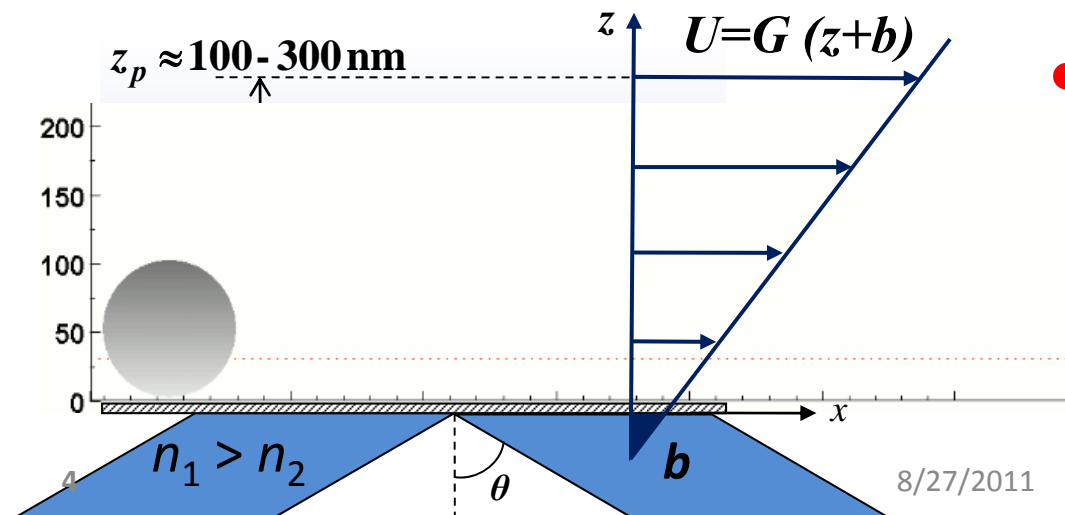
[Li and Yoda, Exp Fluids , 2008]

- Extension of standard (macroscale) PIV
 - Use evanescent-wave illumination: TIR
 - Seed flow with neutrally buoyant fluorescent particles
 - Record tracer particle images over time
 - Particle velocity \approx flow velocity

nPIV: IMPLEMENTATION

- Illuminate flow with evanescent wave from TIR of light at solid-fluid interface
- Occurs at angle of incidence $\theta > \theta_c = \sin^{-1}\left(\frac{n_2}{n_1}\right)$
- Evanescent wave propagates parallel to wall
- Intensity $\propto \exp\{-z / z_p\}$,

$$z_p = \frac{\lambda_0}{4\pi n_1} \left[\sin^2 \theta - \left(\frac{n_2}{n_1} \right)^2 \right]^{-1/2}$$



- Brownian motion causes particle drop out/in illumination region

[Sadr et al., Exp. Fluids, 2005]

BROWNIAN MOTION

- Random motion of submicron particles in a fluid due to thermal energy

$$D_{B\infty} = \frac{kT}{6\pi\mu a}$$

- Brownian diffusion hindered by wall

- Out-of-plane (z) diffusion

[Bevan & Prieve 2000]

$$(a=50\text{nm}, T=300\text{ K}) \quad D_{B\perp} = 0.47 D_{B\infty} \text{ for } h/a = 1$$

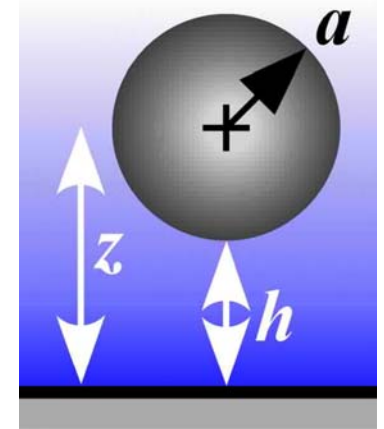
- Over $\Delta t = 6.5\text{ ms}$ ($f = 153\text{ Hz}$)

$$\delta z_{B\perp} = 160\text{ nm for } h/a = 1$$

- Langevin equation

$$\Delta \vec{x} = \sum_{t=0}^{t=\Delta t} \left\{ (\vec{\nabla} \cdot D) \delta t + \chi \delta \vec{r} \right\}$$

- χ = Normally distributed random numbers ; mean=0 , $\sigma=1$



SURFACE FORCESS

- Electrostatic force

- $F_{el} = f_n(k, T, a, \epsilon_0, \epsilon, e, \lambda, \zeta_p, \zeta_w)$

- ϵ = permibility, e = elementary charge

- γ = Debye lengths, ζ = Zeta potential

- [Oberholzer et al., J Chem Phys 1997]

- van der Waals forces

- $F_{vdw} = f_n(z, a)$

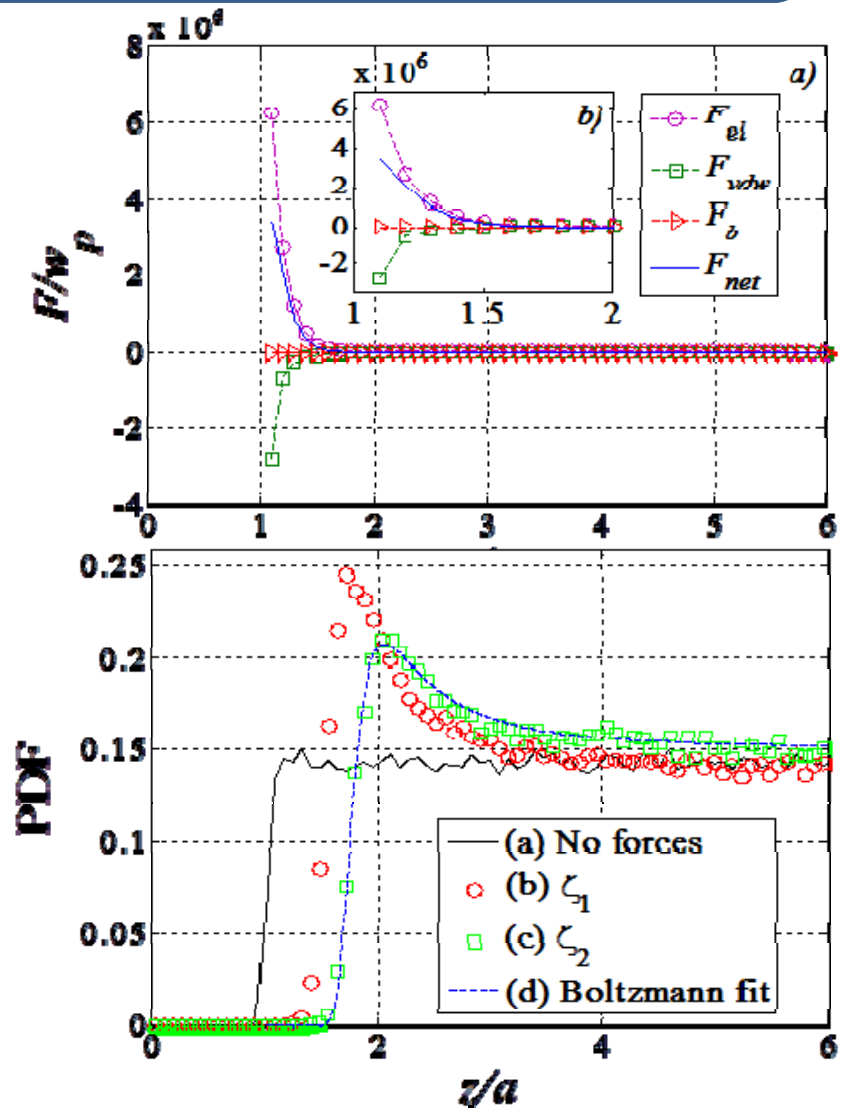
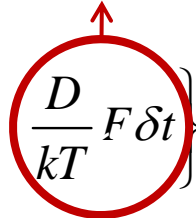
- Buoyancy forces,

- $F_b = f_n(V, \rho_f, \rho_p)$

- Langevin Equation

$$\Delta \vec{x} = \sum_{t=0}^{t=\Delta t} \left\{ (\vec{\nabla} \cdot D) \delta t + \chi \delta \vec{r} + \frac{D}{kT} F \delta t \right\}$$

Surface effects



SIMULATION PARAMETERS

- Tracer: size and number density

- Fluid: velocity profile:

$$U_c = G \cdot \left(\frac{z_v}{2} + a \right)$$

- Shear vs. uniform

- Hindered Brownian motion

- Surface and Buoyancy forces

- Illumination characteristics:

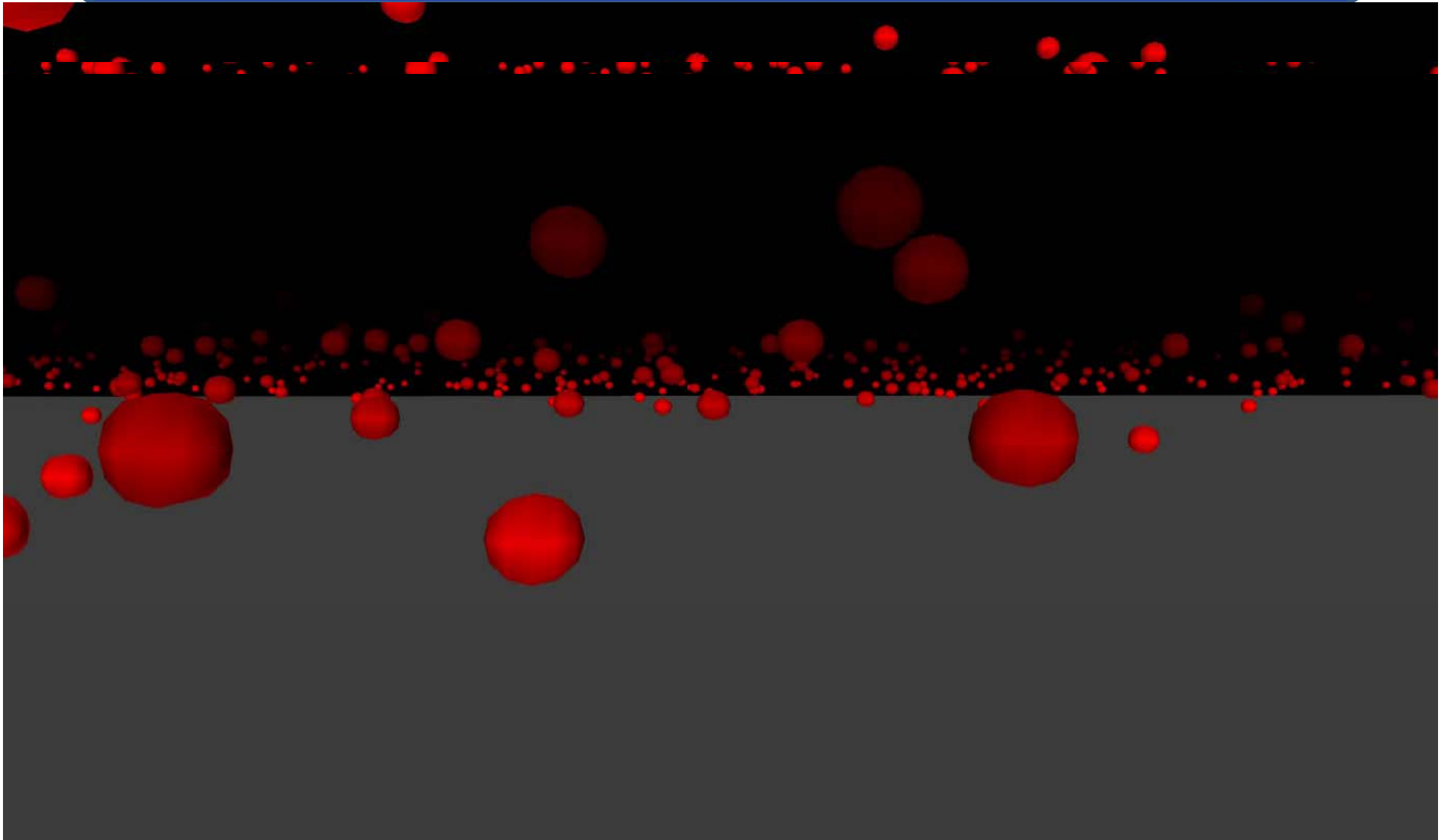
- *Uniform, $Z_v = 280 \text{ nm}$ (non real!)*

- *Linear, $Z_v = 280 \text{ nm}$ (non real!)*

- *Exponentially decaying, $Z_p = 120 \text{ nm}$ (real)*

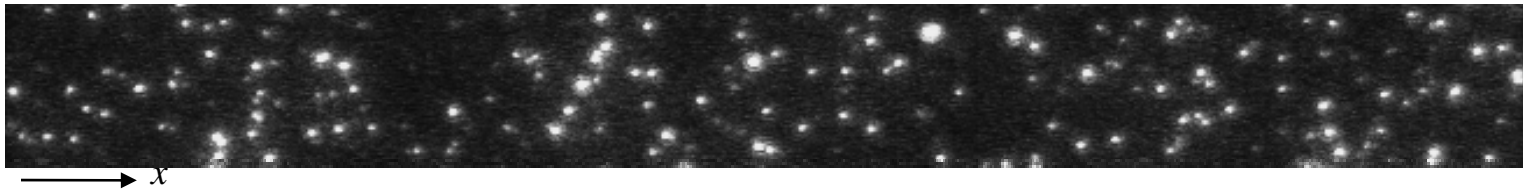
- Camera characteristics: shot and electronic noise

3D VIEW

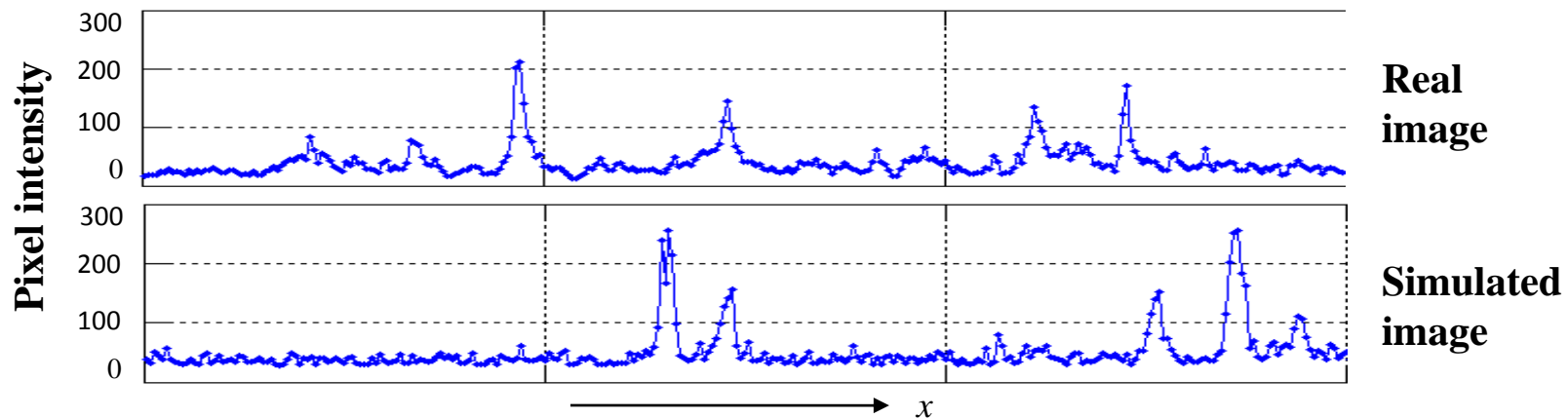
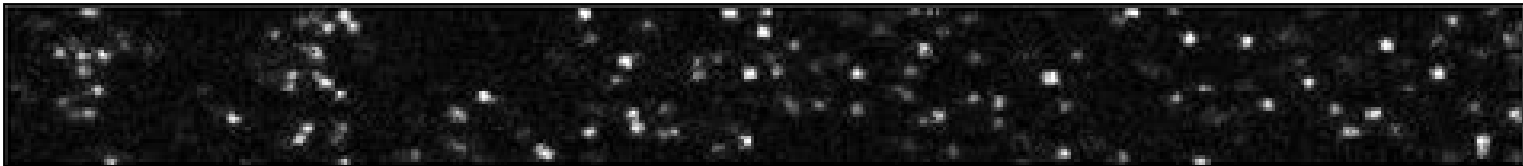


nPIV IMAGES

Real image



Simulated image



- Standard image processing
 - FFT-based cross correlation method to obtain average tracer displacement
 - 2D Gaussian peak-finding algorithm

[Sadr et al., Exp. Fluids, 2005]

[Li et al., Exp. Fluids, 2006]

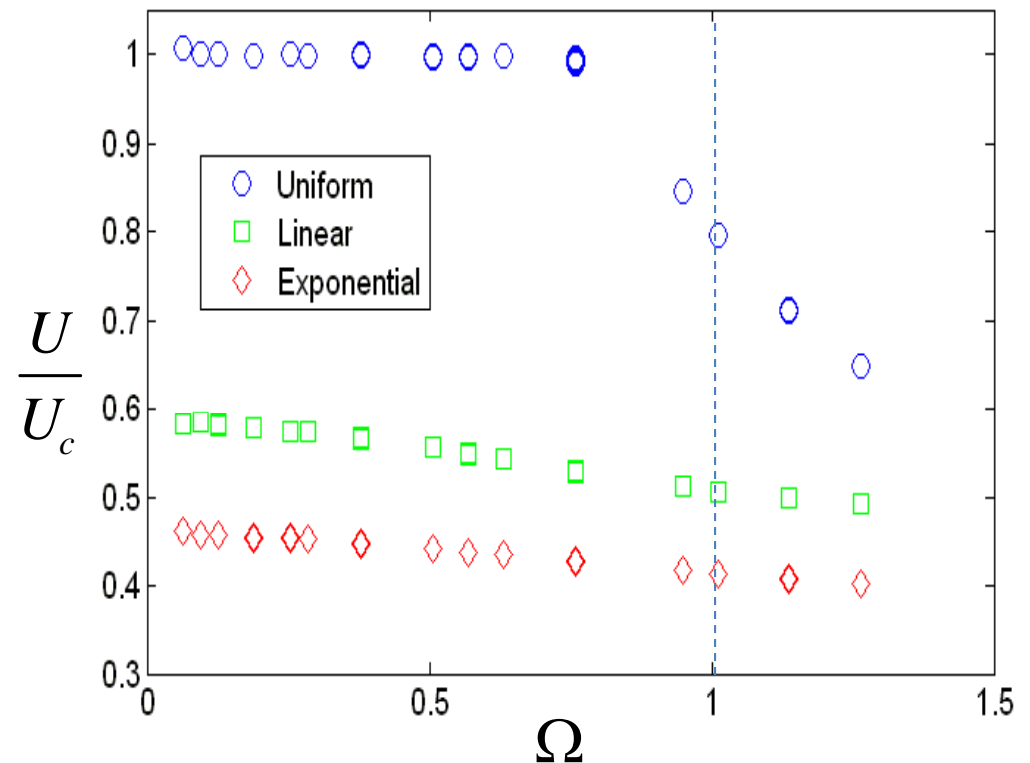


MEASURED MEAN VELOCITY

Shear flow with no Brownian motion

- Light illumination profiles:
 - Uniform, $I = I_0$ for $0 \leq z \leq z_v + a$
 - Linear, $I = \frac{I_{noise} - I_0}{z_v} (z - a) + I_0$
 - Exponential, $I = I_0 \exp\left\{\frac{z}{z_p}\right\}$
- Decaying Light illumination affects measured velocity for shear flow
- Strongest effect is for exponentially decaying light

$$\Omega = \frac{\Delta t \cdot U_c}{r_s} \rightarrow \rightarrow \text{search radius}$$

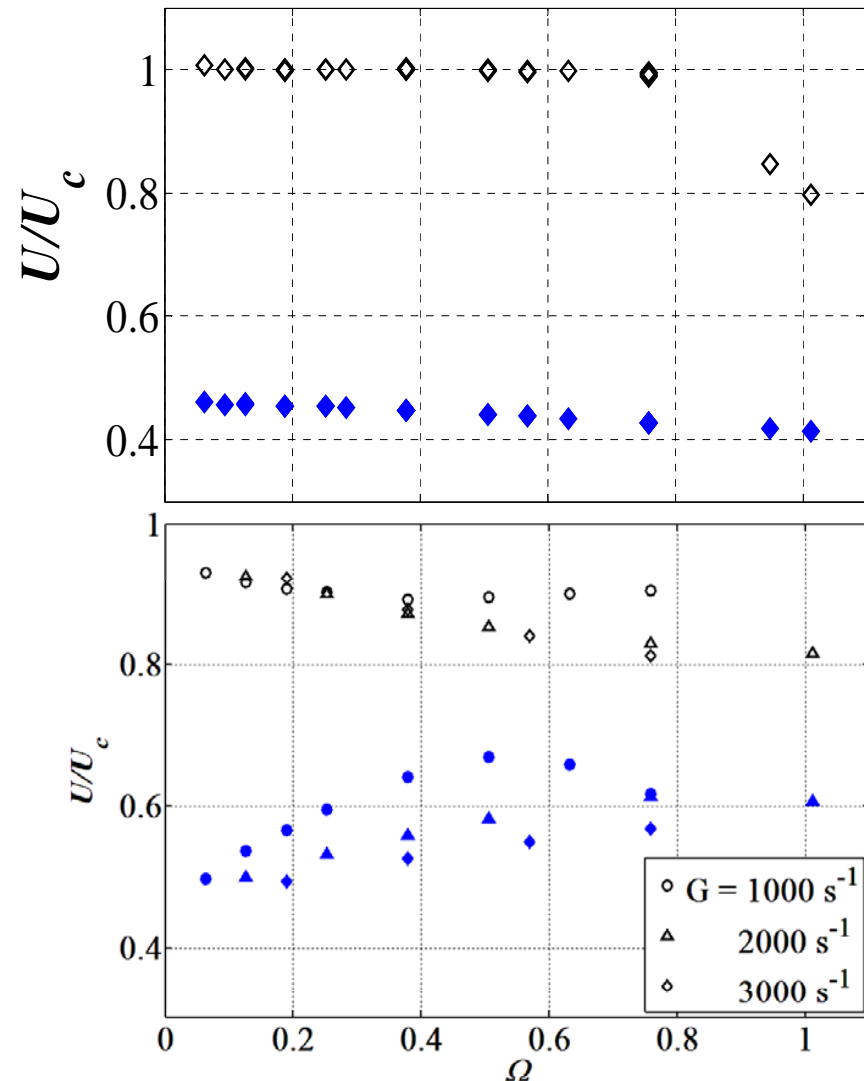


Each line contains all the shear rates study in this work, i.e. $G=1000$ to 3000 s^{-1}

BIAS IN PIV DATA REDUCTION RESULTS

No Surface effects

- Shear flow without Brownian motion
 - Significant effect of illumination
 - Small effect of time delay
 - No affect of shear
- Shear flow with Brownian motion
 - Significant effect for illumination
 - Significant effect for time interval
 - Effect of shear depends on all shear, illumination, and time interval



EFFECT OF CORRECTION FACTORS

Surface effects

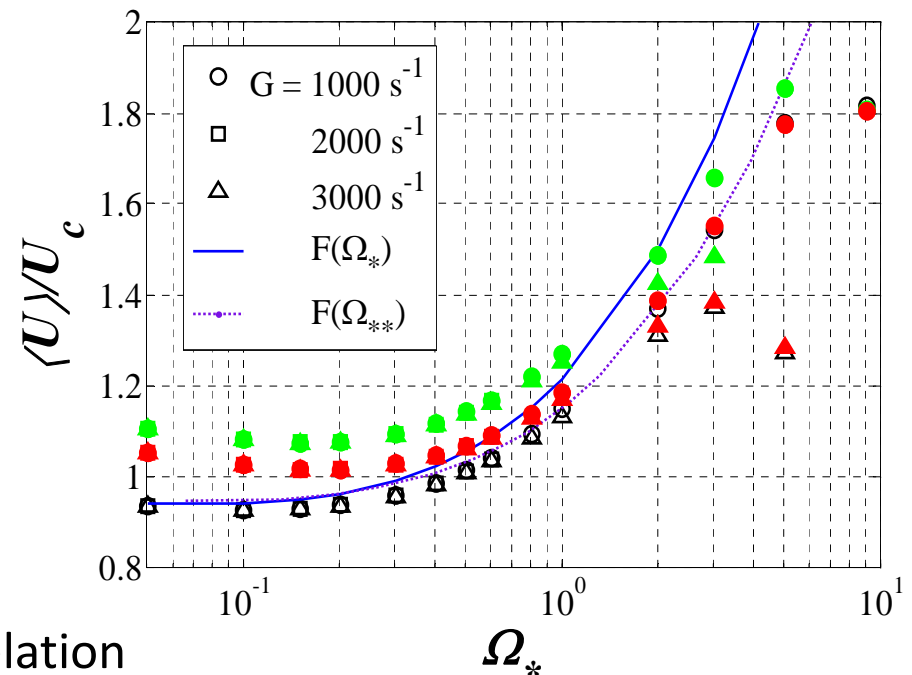
- Correction factors for Brownian motion

[Sadr *et al.*, JFM, 2007]

$$F(\Omega_*) = \langle U \rangle / U_c = 0.21 + (1 - 0.21) \exp\left\{-1.72\sqrt{\Omega_*}\right\} + 0.86\sqrt{\Omega_*}$$

$$\Omega_* = \frac{D_\infty \Delta t}{(z_v + 0.8a)^2}$$

- Surface effects are not considered
 - Based on particle displacement
 - No illumination affects are present
 - $F(\Omega_{**})$ [Huang *et al.*, JFM, 2009]
 - Based on particle displacement
 - No illumination affects are present
- Estimated tracer velocity well predicted
 - The bias pattern is well predicted
 - The models fail to correct the correlation based PIV data reduction results



EXPERIMENTAL RESULTS

- **Inverted epi-fluorescent Leica DMI6000 microscope**

- Adapted for evanescent-wave illumination from Ar⁺ laser
- 40× objective w/adjustable working distance

- **Princeton Pro EM 512**

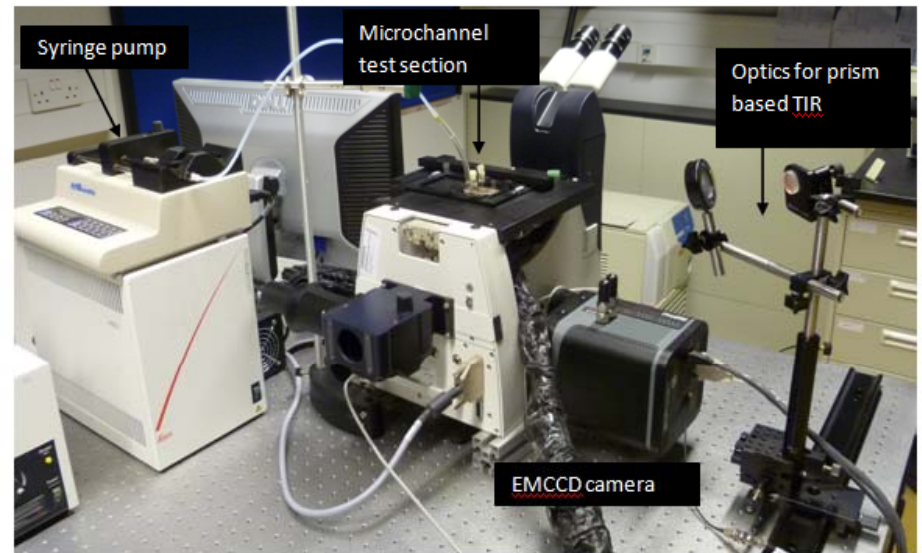
- On-chip gain (no intensifier): quantum effic. ~90% at 500 nm
- Image size 512×100 pixels
- Image pair time delay $\Delta t=1.3\text{ms}$

- **Fused silica micro channel**

- $H=25\ \mu\text{m}$, $W=53\ \mu\text{m}$

- **Constant flow**

- Syringe pump



G (s ⁻¹)	z _v (nm)	Dt (ms)	Correction factor	U _{cal} (m/s) Theory	U _{exp} (m/s) Measured	U _{corr} (m/s) Corrected Velocity
2055	240	2.28	1.29	3.62E-4	2.41E-4	3.12E-4

SUMMARY

- nPIV: Near wall velocity measurement at $Z < 300$ nm
- Surface forces are significant at nano scale and cause non uniform tracer distribution near the wall
- Combination of shear and non uniform illumination also affects obtained velocity using correlation methods
- Existing correction for tracer displacement does not correct for PIV data reduction via correlation method
- Our results partially corrects the underestimation of the obtained velocity

ACKNOWLEDGEMENTS

Thank you

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